

# **METHOD FOR PERFORMING STATISTICAL POST PROCESSING IN SEMICONDUCTOR MANUFACTURING USING ID CELLS**

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## **ABSTRACT OF THE DISCLOSURE**

A method of manufacturing a semiconductor integrated circuit includes providing a fabricated integrated circuit on a wafer. A test fixture is connected to unencapsulated pads on the integrated circuit to monitor an operating parameter for  
10 the circuit and to determine a unique identifier for the die. The parameter is analyzed in post processing.